Form PTO 1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.			SERIAL NO. 2018.		
(Modified)		PAIENIANDIN	DEMARK OFFICE	274523US0PCT			Based on PCT/JP04/00102		
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LIST OF	REFE	RENCES CITED BY AF	PLICANT	Yoshiyuki TAN	Yoshiyuki TANIGUCHI, et al.				
				FILING DATE	Herewith 07/11/2005			GROUP 1755	
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		DOCUMENT NUMBER	DATE		COUNTRY		TRANSLATION		
/LH/	AO	2003-010695	01/14/03	ID/with English at	JP(with English abstract)		YES	S NO	
, , , ,	AP	02/064541	08/22/02	WO				NÓ	
	AQ	60-232247	11/18/85		JP(with English abstract)			NO	
	AR	06-233938	08/23/94		JP(with English abstract)		<u> </u>	NO	
	AS	58-156351	09/17/83		JP(with English abstract)		-	NO	
	AT	06-007685	01/18/94		JP(with English abstract)			NO	
$ \Psi$	AU	08-332387	12/17/96		JP(with English abstract)			NÖ	
/LH/	AV	06-262081	09/20/94		JP(with English abstract)			NO	
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Examiner /	miner /Patricia Hailey/						Date Considered 05/21/2007		
			whether or not	citation is in confor	mance with MPEP 60				
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									